

(19) World Intellectual Property Organization
International Bureau



(43) International Publication Date
31 July 2008 (31.07.2008)

PCT

(10) International Publication Number
WO 2008/091216 A1

- (51) International Patent Classification:
G01B 7/06 (2006.01) G01B 13/06 (2006.01)
- (21) International Application Number:
PCT/SE2008/050077
- (22) International Filing Date: 24 January 2008 (24.01.2008)
- (25) Filing Language: English
- (26) Publication Language: English
- (30) Priority Data:
0700177-9 25 January 2007 (25.01.2007) SE
- (71) Applicant (for all designated States except US): DAPROX AB [SE/SE]; P.O. Box 120, S-127 23 Skärholmen (SE).
- (72) Inventor; and
(75) Inventor/Applicant (for US only): ÅKERBLOM, Bengt [SE/SE]; Vårby Allé 23, S-143 40 Vårby (SE).
- (74) Agent: ALBIHNS AB; P.O. Box 5581, S-114 85 Stockholm (SE).
- (81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IS, JP, KE, KG, KM, KN, KP, KR, KZ, LA, LC, LK, LR, LS, LT, LU, LY, MA, MD, ME, MG, MK, MN, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RS, RU, SC, SD, SE, SG, SK, SL, SM, SV, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, ZA, ZM, ZW.
- (84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV, MC, MT, NL, NO, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).
- Published:
— with international search report

(54) Title: DEVICE FOR MEASURING A LAYER THICKNESS AND A METHOD FOR MANUFACTURING SAID DEVICE

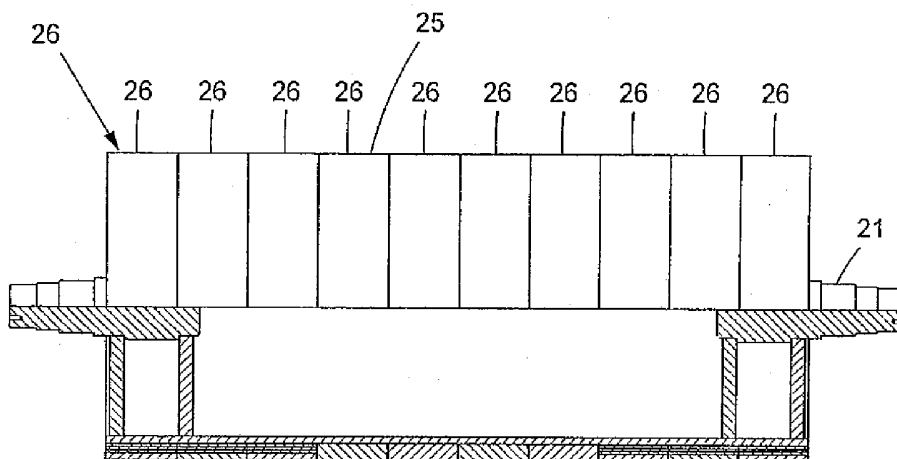


Fig.3

(57) Abstract: Device for measuring thickness of a layer or a coating layer on an elongated strip (10) of material passing by the measuring device. The device comprises means for measuring the thickness in different positions across the width of the elongated strip (10). The means for measuring the thickness is placed in radial direction from a longitudinal axis (21) through a roller (20) that is supporting the elongated strip (10). The means for measuring the thickness comprises a sensor head (12) arranged to rest on a gas cushion generated between the sensor head (12) and the surface of the elongated strip (10), and the outer periphery (25) of the roller (20) is curved in axial direction with a larger diameter towards the ends of the roller (20).

WO 2008/091216 A1